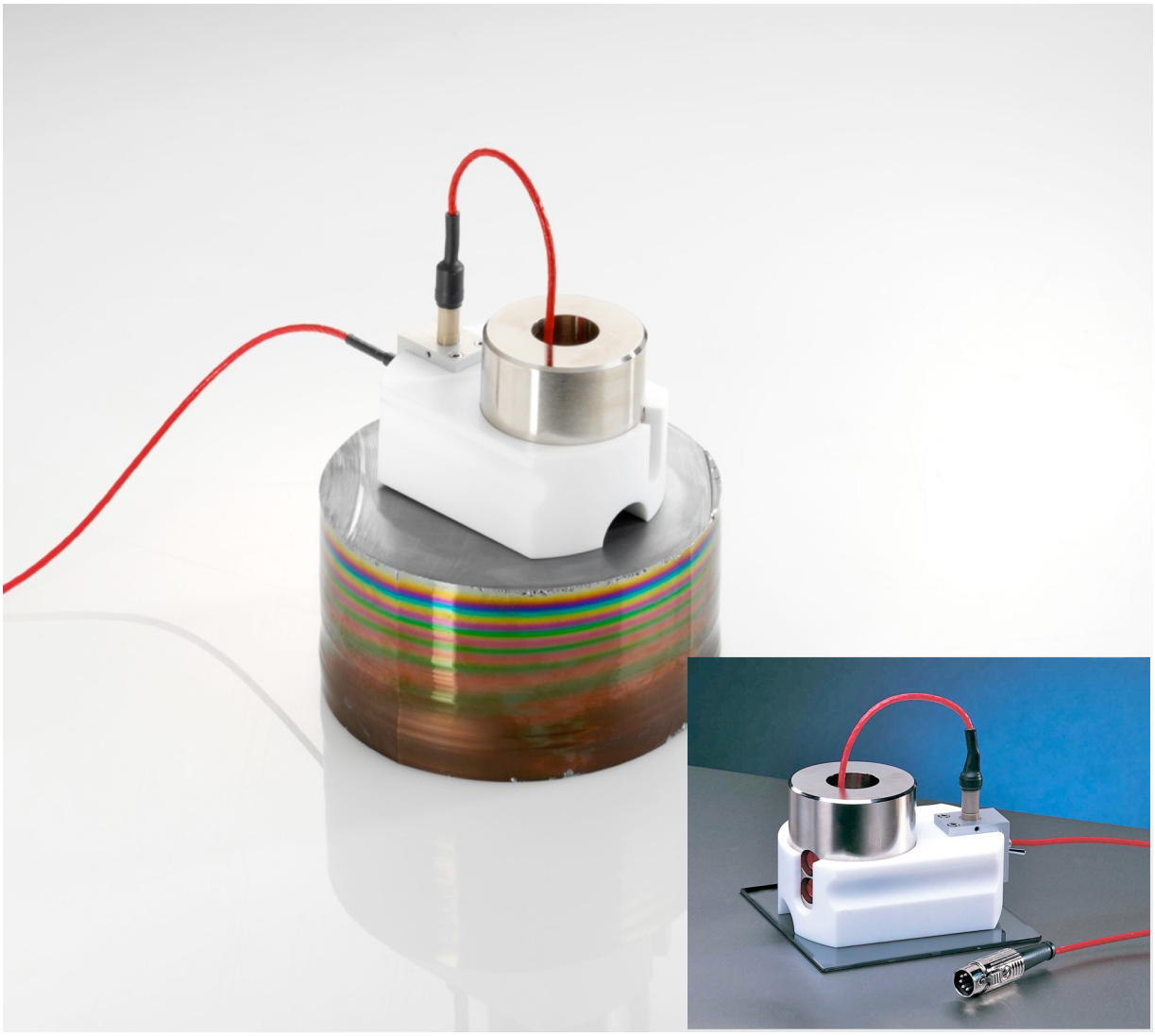
Hand Applied Probe

JANDEL



Jandel Engineering Limited offers the Hand Applied Probe as a solution for making measurements where portability is a key factor. The system can be used for measuring a wide variety of samples from thin layers and wafers up to large ingots. The probe head can have loads of up to 200g per needle and the Hand Applied Probe has a large downward force of around 1.2Kg and so is not suitable for fragile unsupported samples. As a scale for size the main image above shows the Hand Applied Probe sitting on top of a 150mm silicon ingot.

Hand Applied Probe

Max. sample size	Any reasonable size sample can be measured as long as the Hand Applied Probe can be placed appropriately
Max. sample thickness	Any thickness of sample can be measured as long as the Hand Applied Probe can be placed appropriately
Toggle Switch	Prevents current flow when probe is not in contact with the sample
Manual Placement	Probe is designed to be placed and left while measurement is made to avoid fluctuation associated with hand held measurement
Simple set up	Single wire connects the Hand Applied Probe and measurement electronics

Type	Tip	Forc	Spacin
A	*40u*	*100g*	*1mm*
B	*100u*	*100g*	*1mm*
C	*200u*	*100g*	*1mm*
D	*500u*	*70g*	*1mm*
E	*40u*	*200g*	*1.591m*
F	*40u*	*100g*	*0.635m*
G	*100u*	*100g*	*0.635m*
H	*200u*	*100g*	*0.635m*
Type A-D and F-H are user adjustable in the range 60g-150g and supplied at